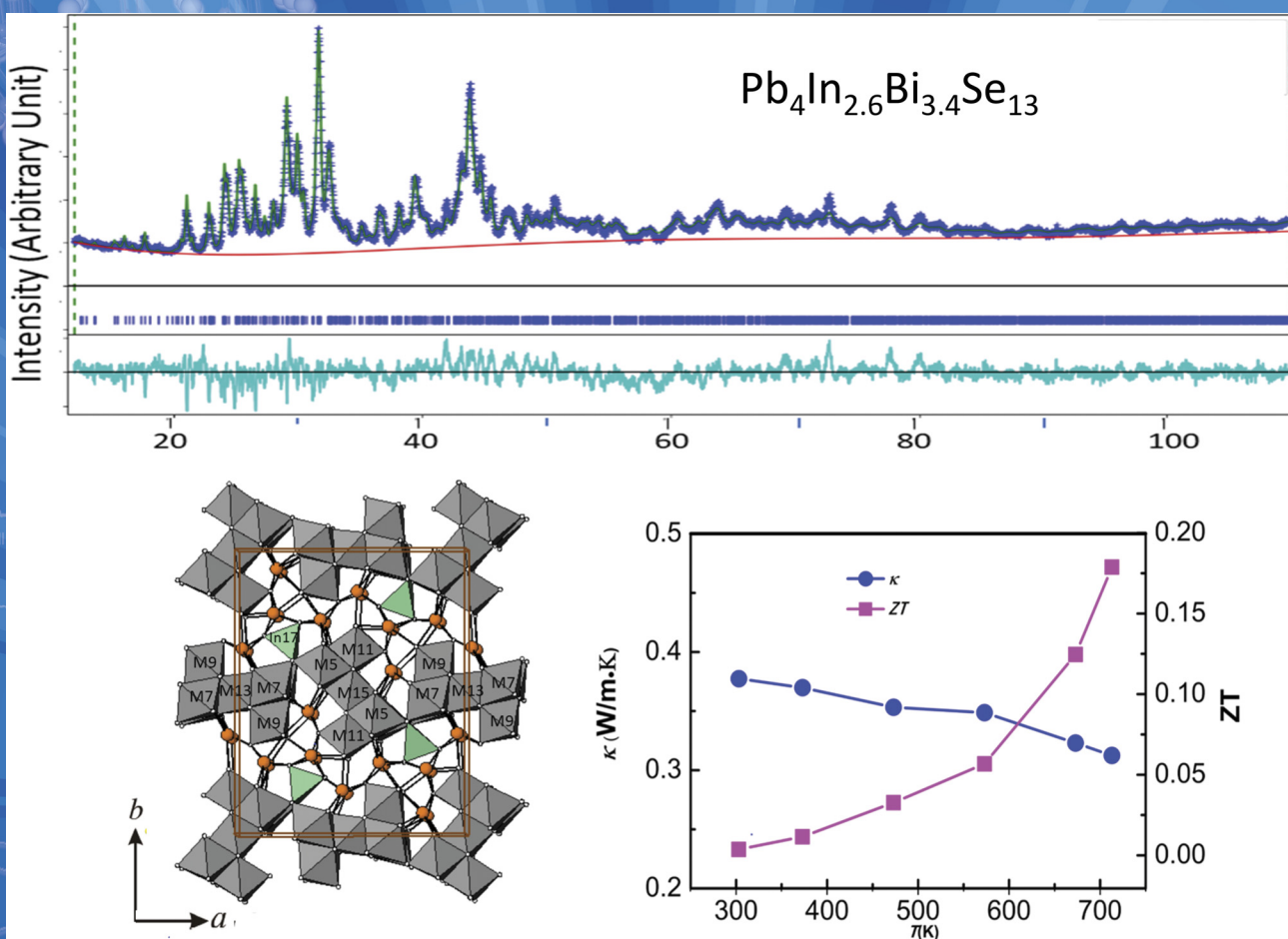


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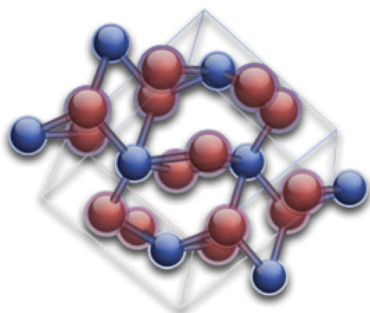
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EDITORIAL

Camden Hubbard Editorial 147

TECHNICAL ARTICLE

Carina Schlesinger,
Edith Alig and
Martin U. Schmidt Crystal structure of the anticancer drug carmustine determined by X-ray powder diffraction 148

W. Wong-Ng, J. Guo,
Y. Yan and J. A. Kaduk Structural and thermoelectric properties of $\text{Pb}_4\text{In}_{2.6}\text{Bi}_{3.4}\text{Se}_{13}$ 151

REVIEW ARTICLE

Hideo Toraya Review of the direct derivation method: quantitative phase analysis with observed intensities and chemical composition data 159

PROCEEDINGS PAPER

Takashi Ida Equatorial aberration for powder diffraction data collected by continuous-scan integration of a silicon strip X-ray detector 196

NEW DIFFRACTION DATA

A. O. Dmitrienko,
A. A. Konnov and
M. S. Klenov Crystal structure of 3-[(3,4-dinitro-1*H*-pyrazol-1-yl)-*NNO*-azoxy]-4-nitro-1,2,5-oxadiazole 176

James A. Kaduk,
Amy M. Gindhart and
Thomas N. Blanton Crystal structure of levocetirizine dihydrochloride Form I, $\text{C}_{21}\text{H}_{27}\text{ClN}_2\text{O}_3\text{Cl}_2$ 181

Joel W. Reid Powder X-ray diffraction data for dimethylarsinic acid, $(\text{CH}_3)_2\text{AsO}(\text{OH})$ 190

James A. Kaduk,
Amy M. Gindhart and
Thomas N. Blanton Crystal structure of palbociclib isethionate Form B, $(\text{C}_{24}\text{H}_{30}\text{N}_7\text{O}_2)(\text{C}_2\text{H}_5\text{O}_4\text{S})$ 196

DATA REPORT

James A. Kaduk,
Amy M. Gindhart and
Thomas N. Blanton Powder X-ray diffraction of varenicline hydrogen tartrate Form B (Chantix[®]), $(\text{C}_{13}\text{H}_{14}\text{N}_3)(\text{HC}_4\text{H}_4\text{O}_6)$ 202

James A. Kaduk,
Amy M. Gindhart and
Thomas N. Blanton Powder X-ray diffraction of pazopanib hydrochloride Form 1, $\text{C}_{21}\text{H}_{24}\text{N}_7\text{O}_2\text{SCl}$ 205

Ryan L. Hodge, James A. Kaduk, Amy M. Gindhart and Thomas N. Blanton	Powder X-ray diffraction of daclatasvir dihydrochloride Form N-2 (Daklinza®), $C_{40}H_{52}N_8O_6Cl_2$	208
---	---	-----

CRYSTALLOGRAPHY EDUCATION NOTE

Stephanie Jennings	ICDD® InSession: Mastering the PDF® Database and JADE® Software	212
--------------------	---	-----

CALENDARS OF MEETINGS, SHORT COURSES AND WORKSHOPS

Gang Wang	Calendar of Forthcoming Meetings	213
Gang Wang	Calendar of Short Courses and Workshops	214

ADDENDUM

Yali Su, Dayong Lu and Shan Wang	Characterization and Rietveld refinements of new dense ceramics $Ba_{3-x}Sr_xTb_{3-x}Ce_xO_9$ ($x = 1$ and 1.5) perovskites – ADDENDUM	215
G. Murugesan, R. Nithya and S. Kalainathan	Rietveld refinement of $Sm_{0.55}Sr_{0.45}Mn_{0.4}Fe_{0.6}O_3$ – ADDENDUM	216

CORRIGENDUM

W. Wong-Ng, G. Y. Liu, D. D. Shi, Y. Q. Yang, R. Derbeshi, D. Windover and J. A. Kaduk	Crystal chemistry, X-ray diffraction reference patterns, and bandgap studies for $(Ba_xSr_{1-x})_2CoWO_6$ ($x = 0.1, 0.2, 0.3, 0.5, 0.7, \text{ and } 0.9$) – CORRIGENDUM	217
---	--	-----

ERRATUM

Gerald Falkenberg, Frank Seiboth, Frieder Koch, Ken Vidar Falch, Andreas Schropp, Dennis Brückner and Jan Garrevoet	CRL optics and silicon drift detector for P06 Microprobe experiments at 35 keV — ERRATUM	218
Anelio J. Dugarte-Dugarte, Jacco van de Streek, Graciela Díaz de Delgado, Alicja Rafalska-Lasocha and José Miguel Delgado	Crystal structure from laboratory X-ray powder diffraction data, DFT-D calculations, Hirshfeld surface analysis, and energy frameworks of a new polymorph of 1-benzothiophene-2-carboxylic acid — ERRATUM	219

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